



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Boyd et al

Serial No. 10/606,022

Filed: June 24, 2003

For: SYSTEM AND METHOD
FOR INTEGRATING IN-SITU
METROLOGY WITHIN A
WAFER PROCESS

Examiner: PERRIN, J.

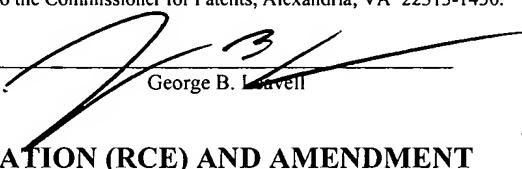
Art Unit: 1746

Atty Docket No. LAM2P425

Date: March 21, 2007

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents and/or fees referred to as attached herein are being deposited with the United States Postal Service on **March 21, 2007** in an envelope as "Express Mail Post Office to Addressee" service under 37 CFR § 1.10, Mailing Label Number **EV979848149** US addressed to the Commissioner for Patents, Alexandria, VA 22313-1450.

Signed: 

George B. Lovell

REQUEST FOR CONTINUED EXAMINATION (RCE) AND AMENDMENT
AND RESPONSE TO ADVISORY ACTION

Commissioner for Patents
Alexandria, VA 22313-1450

In response to the Advisory Action mailed February 21, 2007, Applicant hereby requests an RCE under 37 CFR 1.114. Applicant also requests the following amendments be entered and the following remarks be considered.

Amendments to the Specification begin on page 2 of this paper.

A complete listing of claims with their current status begins on page 3 of this paper.

Remarks begin on page 7 of this paper.

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